

# International Rectifier

PRELIMINARY

# IRG4IBC20FD

## INSULATED GATE BIPOLAR TRANSISTOR WITH ULTRAFAST SOFT RECOVERY DIODE

### Features

- Very Low 1.66V voltage drop
- 2.5kV, 60s insulation voltage ⑤
- 4.8 mm creepage distance to heatsink
- Fast: Optimized for medium operating frequencies ( 1-5 kHz in hard switching, >20 kHz in resonant mode).
- IGBT co-packaged with HEXFRED™ ultrafast, ultrasoft recovery antiparallel diodes
- Tighter parameter distribution
- Industry standard Isolated TO-220 Fullpak™ outline

### Benefits

- Simplified assembly
- Highest efficiency and power density
- HEXFRED™ antiparallel Diode minimizes switching losses and EMI

### Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{CES}$	Collector-to-Emitter Voltage	600	V
$I_c @ T_c = 25^\circ C$	Continuous Collector Current	14.3	A
$I_c @ T_c = 100^\circ C$	Continuous Collector Current	7.7	
$I_{CM}$	Pulsed Collector Current ①	64	
$I_{LM}$	Clamped Inductive Load Current ②	64	
$I_F @ T_c = 100^\circ C$	Diode Continuous Forward Current	6.5	W
$I_{FM}$	Diode Maximum Forward Current	64	
$V_{isol}$	RMS Isolation Voltage, Terminal to Case ⑤	2500	
$V_{GE}$	Gate-to-Emitter Voltage	$\pm 20$	
$P_D @ T_c = 25^\circ C$	Maximum Power Dissipation	34	$^\circ C$
$P_D @ T_c = 100^\circ C$	Maximum Power Dissipation	14	
$T_J$	Operating Junction and	-55 to +150	
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)	
	Mounting Torque, 6-32 or M3 Screw.	10 lbf•in (1.1 N•m)	

### Thermal Resistance

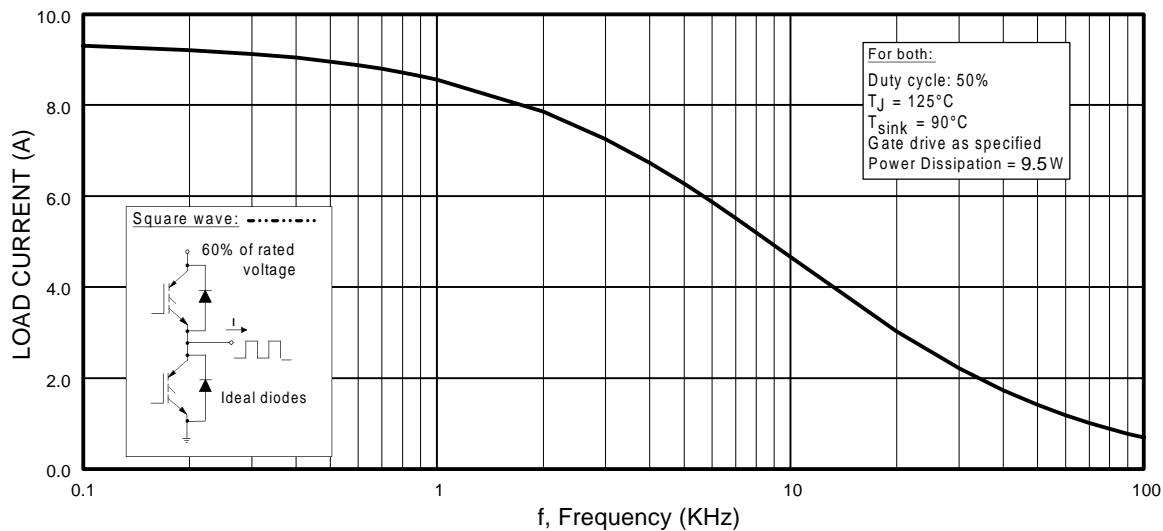
	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case - IGBT	—	3.7	$^\circ C/W$
$R_{\theta JC}$	Junction-to-Case - Diode	—	5.1	
$R_{\theta JA}$	Junction-to-Ambient, typical socket mount	—	65	
$W_t$	Weight	2.0 (0.07)	—	g (oz)

**Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

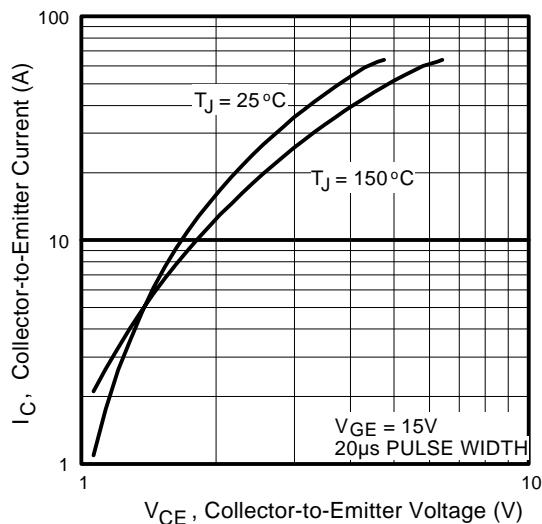
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{CES}}$	Collector-to-Emitter Breakdown Voltage <sup>③</sup>	600	—	—	V	$V_{\text{GE}} = 0\text{V}$ , $I_C = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{CES}/\Delta T_J}$	Temperature Coeff. of Breakdown Voltage	—	0.72	—	$\text{V}/^\circ\text{C}$	$V_{\text{GE}} = 0\text{V}$ , $I_C = 1.0\text{mA}$
$V_{\text{CE}(\text{on})}$	Collector-to-Emitter Saturation Voltage	—	1.66	2.0	V	$I_C = 9.0\text{A}$
		—	2.06	—		$I_C = 16\text{A}$
		—	1.76	—		$I_C = 9.0\text{A}$ , $T_J = 150^\circ\text{C}$
$V_{\text{GE}(\text{th})}$	Gate Threshold Voltage	3.0	—	6.0		$V_{\text{CE}} = V_{\text{GE}}$ , $I_C = 250\mu\text{A}$
$\Delta V_{\text{GE}(\text{th})/\Delta T_J}$	Temperature Coeff. of Threshold Voltage	—	-11	—	$\text{mV}/^\circ\text{C}$	$V_{\text{CE}} = V_{\text{GE}}$ , $I_C = 250\mu\text{A}$
$g_{\text{fe}}$	Forward Transconductance <sup>④</sup>	2.9	5.1	—	S	$V_{\text{CE}} = 100\text{V}$ , $I_C = 9.0\text{A}$
$I_{\text{CES}}$	Zero Gate Voltage Collector Current	—	—	250	$\mu\text{A}$	$V_{\text{GE}} = 0\text{V}$ , $V_{\text{CE}} = 600\text{V}$
		—	—	1700		$V_{\text{GE}} = 0\text{V}$ , $V_{\text{CE}} = 600\text{V}$ , $T_J = 150^\circ\text{C}$
$V_{\text{FM}}$	Diode Forward Voltage Drop	—	1.4	1.7	V	$I_C = 8.0\text{A}$
		—	1.3	1.6		$I_C = 8.0\text{A}$ , $T_J = 150^\circ\text{C}$
$I_{\text{GES}}$	Gate-to-Emitter Leakage Current	—	—	$\pm 100$	nA	$V_{\text{GE}} = \pm 20\text{V}$

**Switching Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

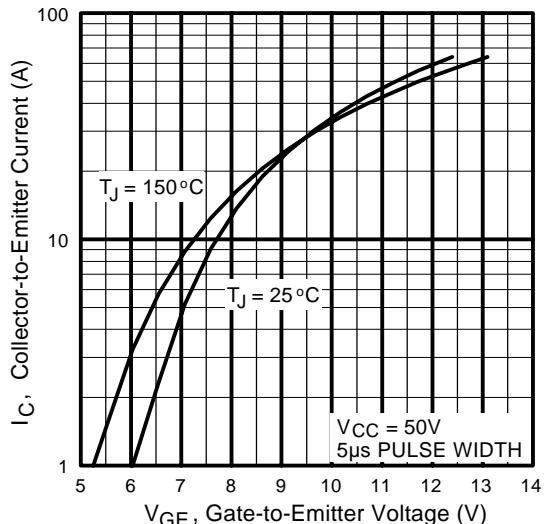
	Parameter	Min.	Typ.	Max.	Units	Conditions
$Q_g$	Total Gate Charge (turn-on)	—	27	40	nC	$I_C = 9.0\text{A}$
$Q_{\text{ge}}$	Gate - Emitter Charge (turn-on)	—	4.2	6.2		$V_{\text{CC}} = 400\text{V}$
$Q_{\text{gc}}$	Gate - Collector Charge (turn-on)	—	9.9	15		$V_{\text{GE}} = 15\text{V}$
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	43	—	ns	$T_J = 25^\circ\text{C}$
$t_r$	Rise Time	—	20	—		$I_C = 9.0\text{A}$ , $V_{\text{CC}} = 480\text{V}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	240	360		$V_{\text{GE}} = 15\text{V}$ , $R_G = 50\Omega$
$t_f$	Fall Time	—	150	220		Energy losses include "tail" and diode reverse recovery. See Fig. 9, 10, 18
$E_{\text{on}}$	Turn-On Switching Loss	—	0.25	—	mJ	
$E_{\text{off}}$	Turn-Off Switching Loss	—	0.64	—		
$E_{\text{ts}}$	Total Switching Loss	—	0.89	1.3		
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	41	—	ns	$T_J = 150^\circ\text{C}$ , See Fig. 11, 18
$t_r$	Rise Time	—	22	—		$I_C = 9.0\text{A}$ , $V_{\text{CC}} = 480\text{V}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	320	—		$V_{\text{GE}} = 15\text{V}$ , $R_G = 50\Omega$
$t_f$	Fall Time	—	290	—		Energy losses include "tail" and diode reverse recovery.
$E_{\text{ts}}$	Total Switching Loss	—	1.35	—	mJ	
$L_E$	Internal Emitter Inductance	—	7.5	—	nH	Measured 5mm from package
$C_{\text{ies}}$	Input Capacitance	—	540	—	pF	$V_{\text{GE}} = 0\text{V}$
$C_{\text{oes}}$	Output Capacitance	—	37	—		$V_{\text{CC}} = 30\text{V}$
$C_{\text{res}}$	Reverse Transfer Capacitance	—	7.0	—		See Fig. 7 $f = 1.0\text{MHz}$
$t_{\text{rr}}$	Diode Reverse Recovery Time	—	37	55	ns	$T_J = 25^\circ\text{C}$ See Fig.
		—	55	90		$T_J = 125^\circ\text{C}$ 14
$I_{\text{rr}}$	Diode Peak Reverse Recovery Current	—	3.5	5.0	A	$T_J = 25^\circ\text{C}$ See Fig.
		—	4.5	8.0		$T_J = 125^\circ\text{C}$ 15
$Q_{\text{rr}}$	Diode Reverse Recovery Charge	—	65	138	nC	$T_J = 25^\circ\text{C}$ See Fig.
		—	124	360		$T_J = 125^\circ\text{C}$ 16
$dI_{(\text{rec})\text{M}}/dt$	Diode Peak Rate of Fall of Recovery During $t_b$	—	240	—	A/ $\mu\text{s}$	$T_J = 25^\circ\text{C}$ See Fig.
		—	210	—		$T_J = 125^\circ\text{C}$ 17



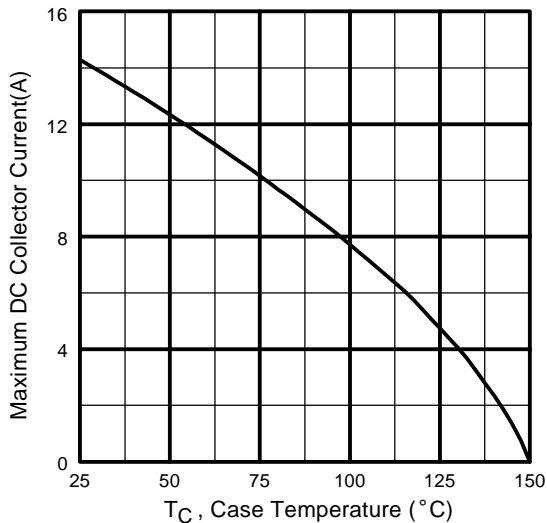
**Fig. 1 - Typical Load Current vs. Frequency**  
(Load Current =  $I_{RMS}$  of fundamental)



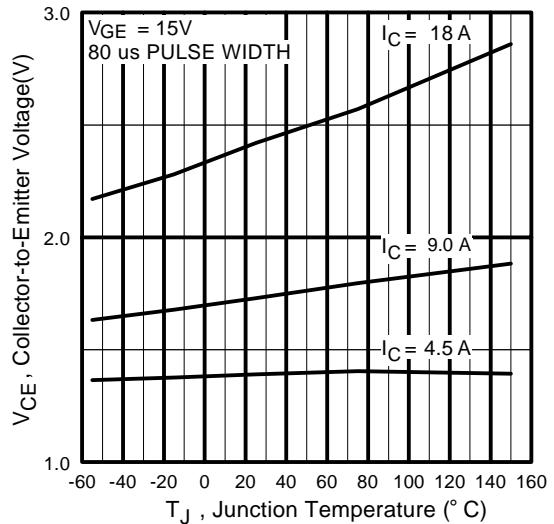
**Fig. 2 - Typical Output Characteristics**



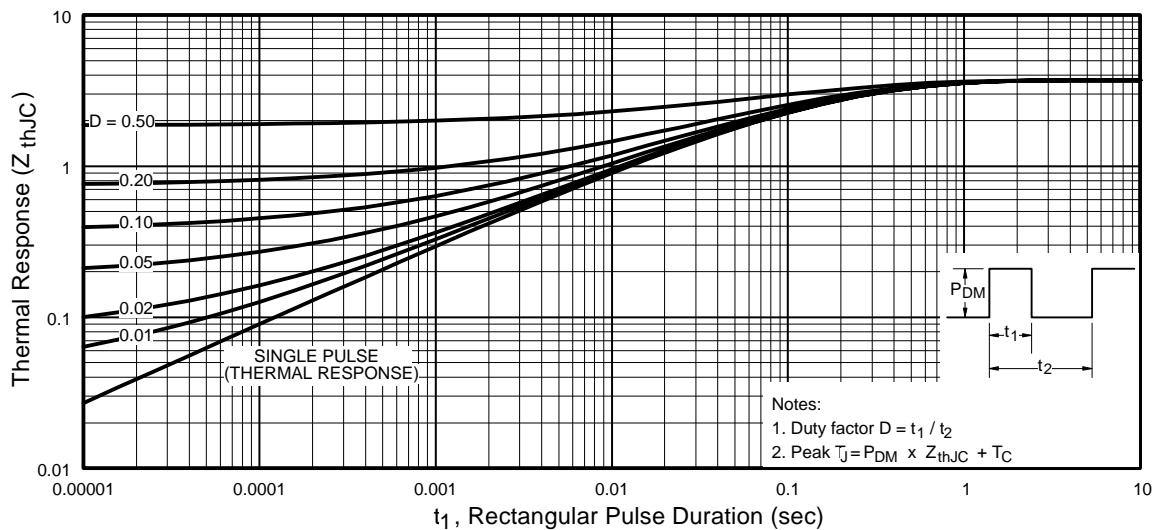
**Fig. 3 - Typical Transfer Characteristics**



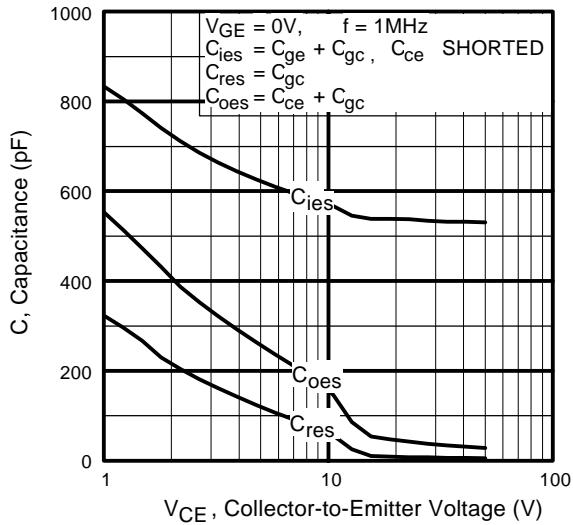
**Fig. 4 - Maximum Collector Current vs. Case Temperature**



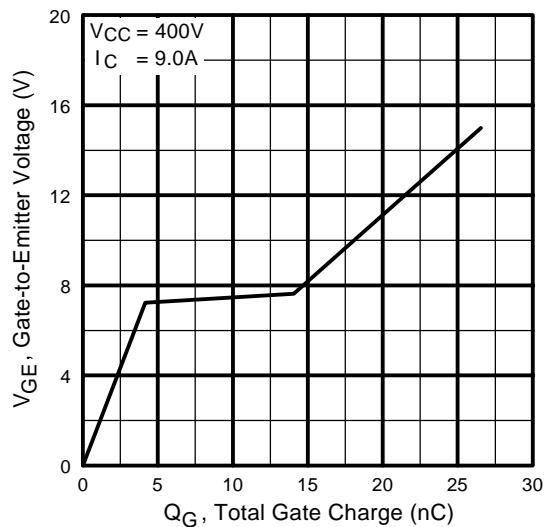
**Fig. 5 - Typical Collector-to-Emitter Voltage vs. Junction Temperature**



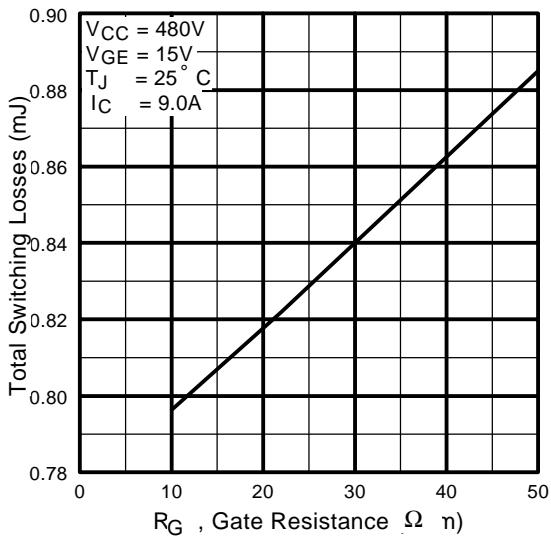
**Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case**



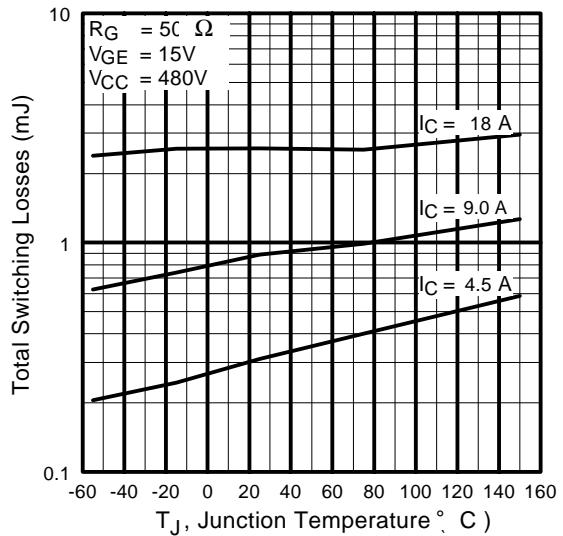
**Fig. 7 - Typical Capacitance vs. Collector-to-Emitter Voltage**



**Fig. 8 - Typical Gate Charge vs. Gate-to-Emitter Voltage**



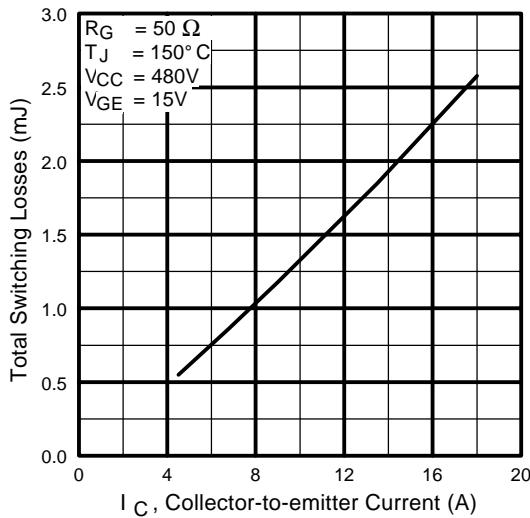
**Fig. 9 - Typical Switching Losses vs. Gate Resistance**



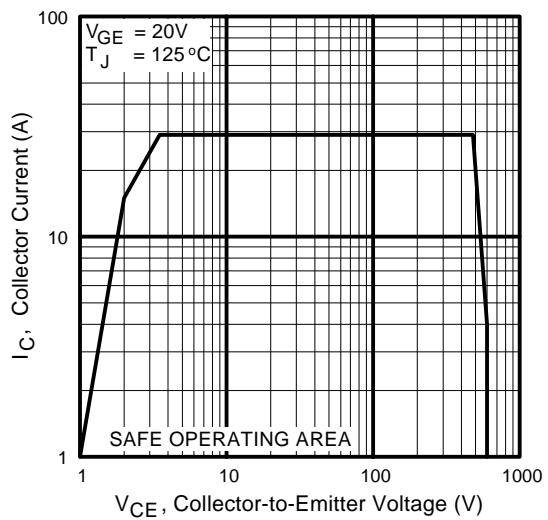
**Fig. 10 - Typical Switching Losses vs. Junction Temperature**

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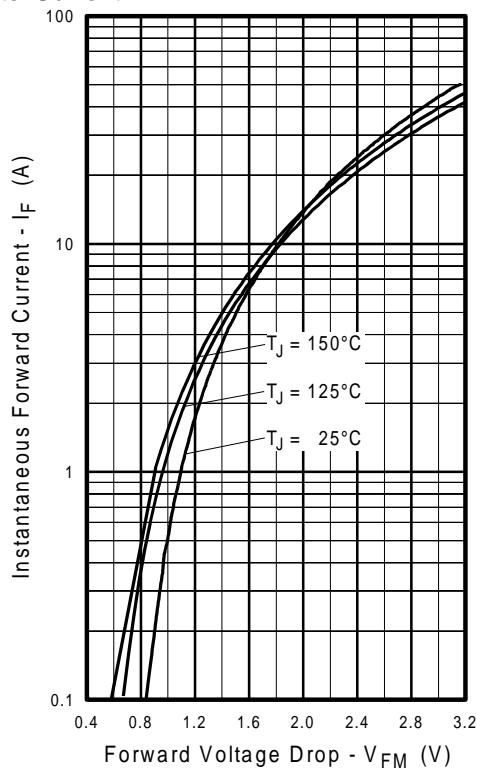
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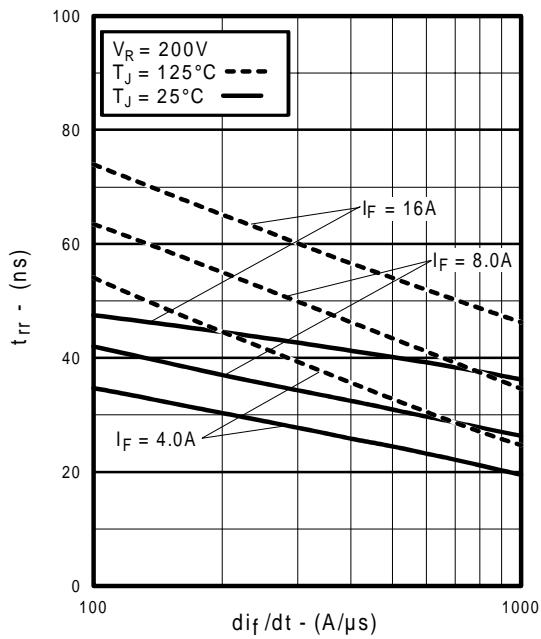
**Fig. 11** - Typical Switching Losses vs.  
Collector-to-Emitter Current



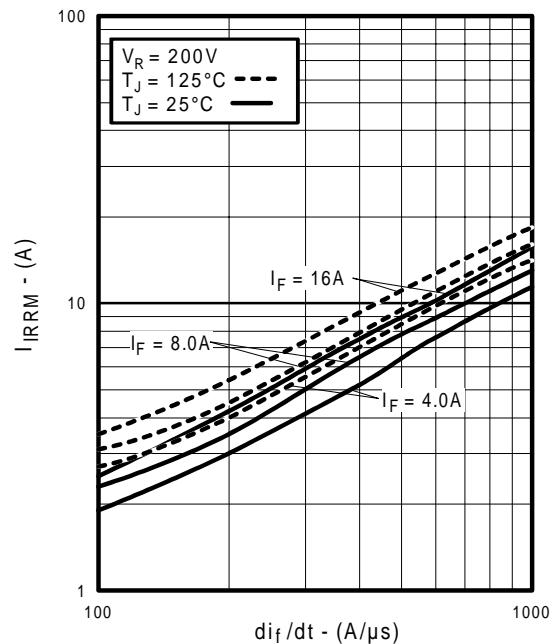
**Fig. 12** - Turn-Off SOA



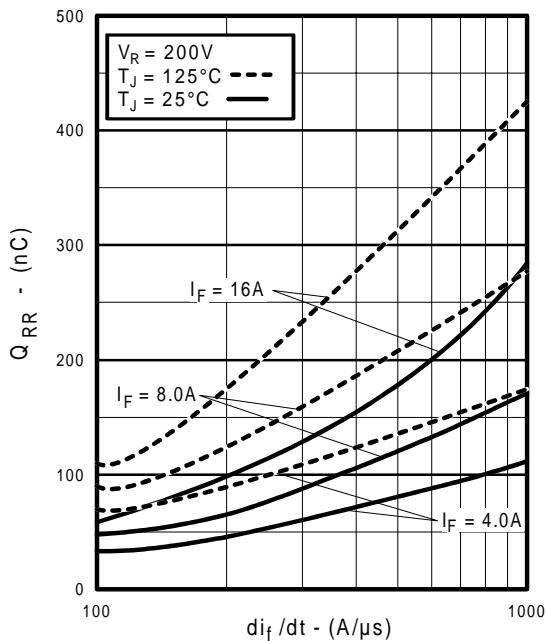
**Fig. 13** - Maximum Forward Voltage Drop vs. Instantaneous Forward Current



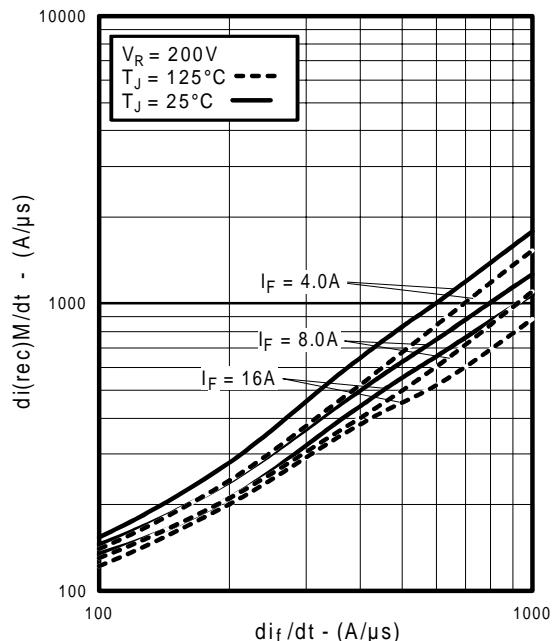
**Fig. 14 - Typical Reverse Recovery vs.  $di_f/dt$**



**Fig. 15 - Typical Recovery Current vs.  $di_f/dt$**



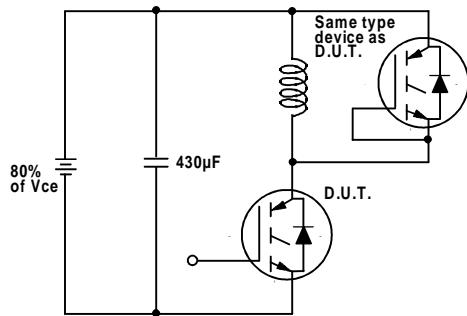
**Fig. 16 - Typical Stored Charge vs.  $di_f/dt$**



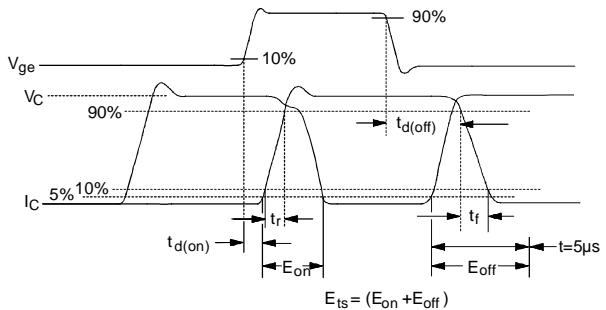
**Fig. 17 - Typical  $di_{(rec)}M/dt$  vs.  $di_f/dt$**

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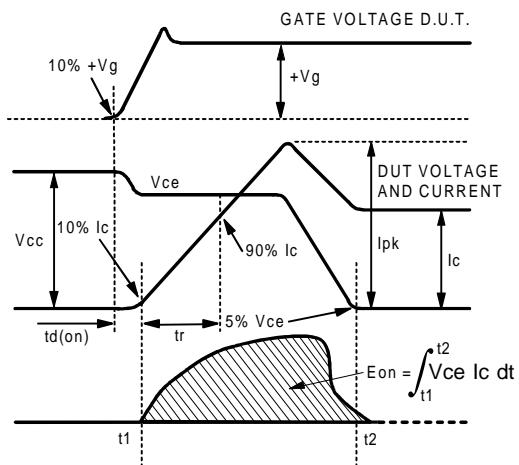
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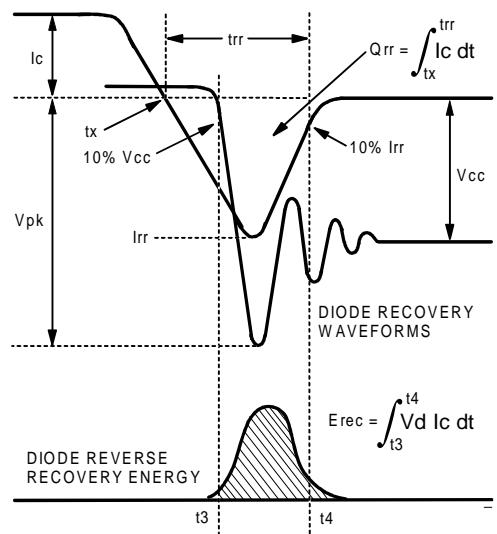
**Fig. 18a** - Test Circuit for Measurement of  $I_{LM}$ ,  $E_{on}$ ,  $E_{off(diode)}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$ ,  $t_{d(on)}$ ,  $t_r$ ,  $t_{d(off)}$ ,  $t_f$



**Fig. 18b** - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{off}$ ,  $t_{d(off)}$ ,  $t_f$



**Fig. 18c** - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{on}$ ,  $t_{d(on)}$ ,  $t_r$



**Fig. 18d** - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{rec}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$

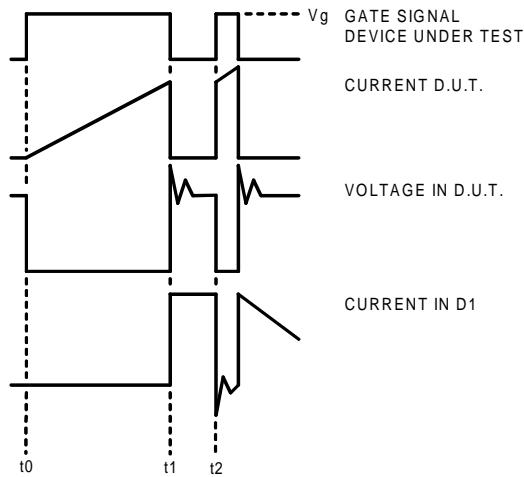


Figure 18e. Macro Waveforms for Figure 18a's Test Circuit

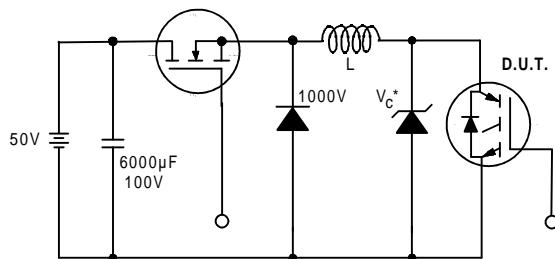


Figure 19. Clamped Inductive Load Test Circuit

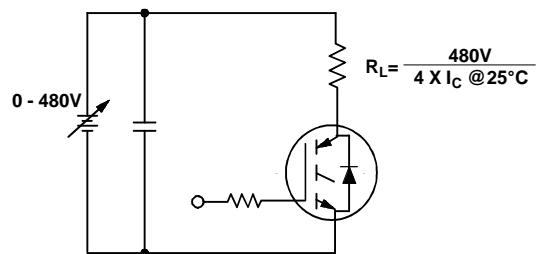
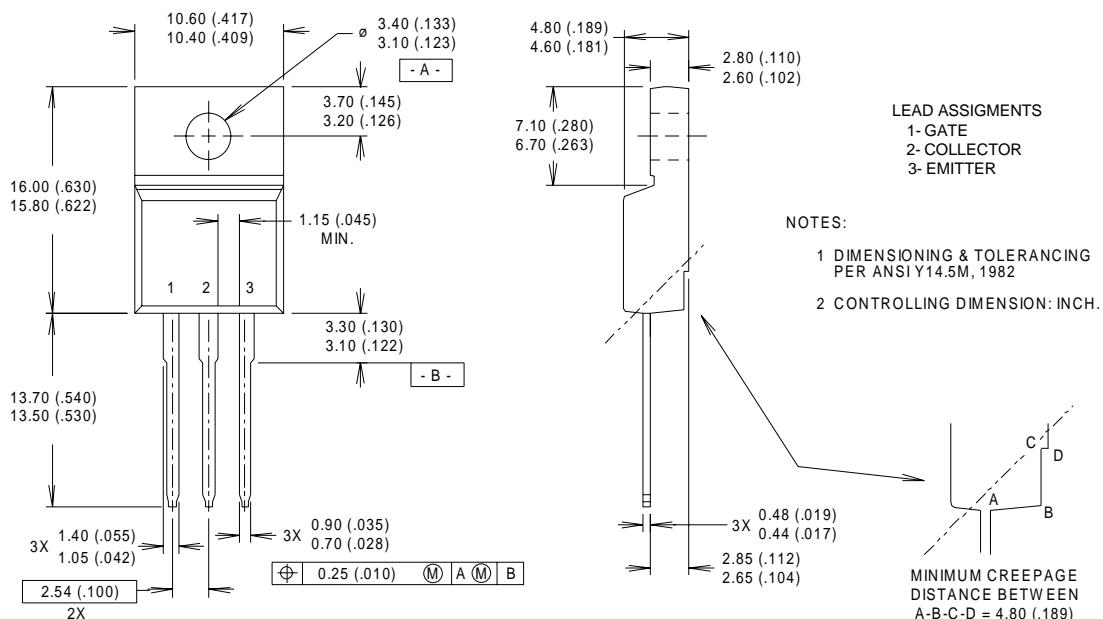


Figure 20. Pulsed Collector Current Test Circuit

## Notes:

- ① Repetitive rating:  $V_{GE}=20V$ ; pulse width limited by maximum junction temperature (figure 20)
- ②  $V_{CC}=80\% (V_{CES})$ ,  $V_{GE}=20V$ ,  $L=10\mu H$ ,  $R_G = 50\Omega$  (figure 19)
- ③ Pulse width  $\leq 80\mu s$ ; duty factor  $\leq 0.1\%$ .
- ④ Pulse width  $5.0\mu s$ , single shot.
- ⑤  $t = 60s$ ,  $f = 60Hz$

## Case Outline — TO-220 FULLPAK



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